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- Low Noise
- No External Components Required
- Replaces Chopper Amplifiers at a Lower Cost
- Single-Chip Monolithic Fabrication
- Wide Input Voltage Range 0 to ±14 V Typ
- Wide Supply Voltage Range ±3 V to ±18 V
- Essentially Equivalent to Fairchild μA714 Operational Amplifiers
- Direct Replacement for PMI OP07C and OP07D



NC-No internal connection

symbol



description

These devices represent a breakthrough in operational amplifier performance. Low offset and long-term stability are achieved by means of a low-noise, chopperless, bipolar-input-transistor amplifier circuit. For most applications, external components are not required for offset nulling and frequency compensation. The true differential input, with a wide input voltage range and outstanding common-mode rejection, provides maximum flexibility and performance in high-noise environments and in noninverting applications. Low bias currents and extremely high input impedances are maintained over the entire temperature range. The OP07 is unsurpassed for low-noise, high-accuracy amplification of very low-level signals.

These devices are characterized for operation from 0°C to 70°C.

	Viemov	PACKAGED							
TA	AT 25°C	SMALL OUTLINE (D)	PLASTIC DIP (P)	(Y)					
0°C to 70°C	150 μV	OP07CD OP07DD	OP07CP OP07DP	OP07Y					

AVAILABLE OPTIONS

The D package is available taped and reeled. Add the suffix R to the device type (e.g., OP07CDR). The chip form is tested at $T_A = 25^{\circ}$ C.



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OP07Y chip information

These chips, properly assembled, display characteristics similar to the OP07. Thermal compression or ultrasonic bonding may be used on the doped-aluminum bonding pads. Chips may be mounted with conductive epoxy or a gold-silicon preform.





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC+} (see Note 1)	22 V
Supply voltage, V _{CC}	–22 V
Differential input voltage (see Note 2)	±30 V
Input voltage, VI (either input, see Note 3)	±22 V
Duration of output short circuit (see Note 4)	unlimited
Continuous total dissipation at (or below) 25°C free-air temperature (see Note 5)	500 mW
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

NOTES: 1. All voltage values, unless otherwise noted, are with respect to the midpoint between V_{CC+} and V_{CC-}.

- 2. Differential voltages are at IN+ with respect to IN-.
- 3. The magnitude of the input voltage must never exceed the magnitude of the supply voltage or 15 V, whichever is less.
- 4. The output may be shorted to ground or either power supply.
- 5. For operation above 64°C free-air temperature, derate the D package to 464 mW at 70°C at the rate of 5.8 mW/°C.

recommended operating conditions

		MIN	MAX	UNIT
Supply voltage, V _{CC±}				V
Common-mode input voltage, VIC	V _{CC±} = ±15 V	-13	13	V
Operating free-air temperature, T _A		0	70	°C



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OP07D OP07C PARAMETER UNIT **TEST CONDITIONS[†]** TΑ MAX TYP MAX MIN TYP MIN 25°C 60 150 60 150 VIO Input offset voltage $V_{O} = 0$, $R_S = 50 \Omega$ μV 0°C to 70°C 85 250 250 85 Temperature coefficient of input offset voltage $V_{O} = 0,$ $R_S = 50 \Omega$ 0°C to 70°C 0.5 1.8 0.7 2.5 uV/°C ανιο Long-term drift of input offset voltage See Note 6 0.4 0.5 μV/mo Offset adjustment range $R_S = 20 k\Omega$, See Figure 1 25°C ±4 ±4 mV 25°C 6 0.8 0.8 6 Input offset current 10 nA 8 8 0°C to 70°C 1.6 1.6 Temperature coefficient of input offset current 0°C to 70°C 12 50 12 50 pA/°C αΙΙΟ ±7 ±12 25°C ±1.8 ±2 Input bias current nA IВ 0°C to 70°C ±2.2 ±9 ±З ±14 Temperature coefficient of input bias current 50 0°C to 70°C 18 18 50 pA/°C αIIB 25°C ±13 ±14 ±13 ±14 VICR Common-mode input voltge range V 0°C to 70°C ±13 ±13.5 ±13 ±13.5 $R_{I} \ge 10 \ k\Omega$ ±12 ±13 ±12 ±13 $R_{I} \ge 2 k\Omega$ 25°C ±12.8 ±11.5 ±12.8 ±11.5 ۷ом Peak output voltage V $R_{I} \ge 1 k\Omega$ ±12 ±12 $R_{I} \ge 2 k\Omega$ 0°C to 70°C ±12.6 ±11 ±12.6 ±11 $V_{CC \pm} = \pm 3 \text{ V}, \quad V_{O} = \pm 0.5 \text{ V},$ 25°C 400 400 100 $R_{I} \ge 500 \text{ k}\Omega$ Large-signal differential voltage amplification V/mV AVD 25°C 120 400 120 400 $V_{O} = \pm 10 V$, $R_{I} = 2 k\Omega$ 0°C to 70°C 100 400 100 400 B1 Unity-gain bandwidth 25°C 0.4 0.6 0.4 0.6 MHz 25°C 8 33 7 31 MΩ Input resistance ri 25°C 100 120 94 110 CMRR Common-mode rejection ratio dB $V_{IC} = \pm 13 \text{ V}, \text{ R}_{S} = 50 \Omega$ $0^{\circ}C$ to $70^{\circ}C$ 120 94 106 97 7 25°C 32 7 32 $V_{CC\pm} = \pm 3 V \text{ to } \pm 18 V,$ ksvs Supply voltage sensitivity $(\Delta V_{IO}/\Delta V_{CC})$ μV/V $R_S = 50 \Omega$ $0^{\circ}C$ to $70^{\circ}C$ 10 51 10 51 $V_{O} = 0,$ No load 80 150 80 150 $V_{CC\pm} = \pm 3 \text{ V}, \quad V_{O} = 0,$ PD Power dissipation 25°C mW 4 8 8 4 No load

electrical characteristics at specified free-air temperature, $V_{CC} \pm = \pm 15$ V (unless otherwise noted)

[†] All characteristics are measured under open-loop conditions with zero common-mode input voltage unless otherwise noted.

NOTE 6: Since long-term drift cannot be measured on the individual devices prior to shipment, this specification is not intended to be a warranty. It is an engineering estimate of the averaged trend line of drift versus time over extended periods after the first thirty days of operation.

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operating characteristics, $V_{CC\pm} = \pm 15 \text{ V}$, $T_A = 25^{\circ}C$

PARAMETER		TEST	OP07C			OP07D			LINUT	
		CONDITIONS [†]	MIN	ТҮР	MAX	MIN	TYP	MAX	UNIT	
v _n	Equivalent input noise voltage	f = 10 Hz		10.5			10.5			
		f = 100 Hz		10.2			10.3		nV/√Hz	
		f = 1 kHz		9.8			9.8			
V _{N(PP)}	Peak-to-peak equivalent input noise voltage	f = 0.1 Hz to 10 Hz		0.38			0.38		μV	
۱ _n	Equivalent input noise current	f = 10 Hz		0.35			0.35			
		f = 100 Hz		0.15			0.15		pA/√Hz	
		f = 1 kHz		0.13			0.13			
I _{N(PP)}	Peak-to-peak equivalent input noise current	f = 0.1 Hz to 10 Hz		15			15		pА	
SR	Slew rate	R _L ≥ 2 kΩ		0.3			0.3		V/µs	

[†] All characteristics are measured under open-loop conditions with zero common-mode input voltage unless otherwise noted.

electrical characteristics, V_{CC\pm} = ± 15 V, T_A = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS [†]		OP07Y				
				MIN	TYP	MAX	UNIT	
VIO	Input offset voltage	R _S = 50 Ω				60	150	μV
	Long-term drift of input offset voltage	See Note 6				0.5		μV/mo
	Offset adjustment range	R _S = 20 kΩ,	See Figure 1			±4		mV
lio	Input offset current					0.8	6	nA
IIB	Input bias current					±2	±12	nA
VICR	Common-mode input voltage range				±13	±14		V
V _{OM}	Peak output voltage	R _L ≤ 10 kΩ			±12	±13		
		R _L ≤ 2 kΩ		±11.5	±12.8		V	
		R _L ≤ 1 kΩ				±12		
AVD	Large-signal differential voltage amplification	$V_{CC\pm} = \pm 3 V$,	$V_{O} = \pm 0.5 V$,	RL ≤ 500 kΩ		400		
		$V_{O} = \pm 10 V$,	$R_L = 2 k\Omega$		120	400		
B ₁	Unity-gain bandwidth				0.4	0.6		MHz
r _i	Input resistance				7	31		MΩ
CMRR	Common-mode input resistance	$V_{IC} = \pm 13 V$,	R _S = 50 Ω		94	110		dB
k SVS	Supply-voltage rejection ratio ($\Delta V_{CC} / \Delta V_{IO}$)	$V_{CC\pm} = \pm 3 V t_{CC\pm}$	o ±18 V,	R _S = 50 Ω		7	32	μV/V
P-	Power dissipation	V _O = 0,	No load			80	150	MO
PD D		$V_{CC\pm} = \pm 3 V,$	V _O = 0,	No load		4	8	

NOTE 6: Since long-term drift cannot be measured on the individual devices prior to shipment, this specification is not intended to be a warranty. It is an engineering estimate of the averaged trend line of drift versus time over extended periods after the first thirty days of operation.



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operating characteristics, V_{CC\pm} = ± 15 V, T_A = 25°C

PARAMETER		TEST CONDITIONST	OP07Y			LINUT	
		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
Vn	Equivalent input noise voltage	f = 10 Hz		10.5			
		f = 1 kHz		10.3		nV/√Hz	
		f = 0.1 Hz to 10 Hz		9.8			
V _{N(PP)}	Peak-to-peak equivalent input noise voltage	f = 0.1 Hz to 10 Hz		0.38		μV	
In	Equivalent input noise current	f = 10 Hz		0.35			
		f = 100 Hz		0.15		pA/√Hz	
		f = 1 kHz		0.13			
I _{N(PP)}	Peak-to-peak equivalent input noise current	f = 0.1 Hz to 10 Hz		15		pА	
SR	Slew rate	$R_L = 2 k\Omega$		0.3		V/μs	

[†] All characteristics are measured under open-loop conditions with zero common-mode input voltage unless otherwise noted.

APPLICATION INFORMATION



Figure 1. Input Offset Voltage Null Circuit



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